

30V,10A N-CHANNEL POWER MOSFET

GENERAL DESCRIPTION

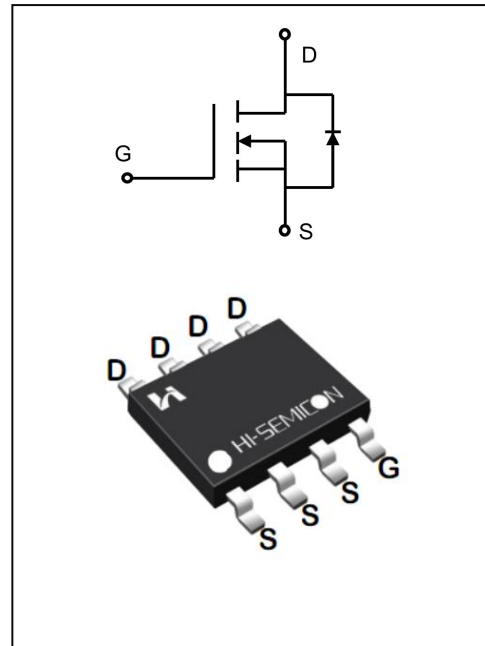
The SFS3001T uses advanced trench technology and design to provide excellent $R_{DS(on)}$ with low gate charge. It can be used in a wide variety applications.

Features

- ◆ $V_{DS}=30V, I_D=10A$
- ◆ $R_{DS(on)}$
 TYP: $9.0m\Omega @ V_{GS}=10V$
 TYP: $14m\Omega @ V_{GS}=4.5V$

Applications

- ◆ Power facion correction (PFC)
- ◆ Switched mode power supplies (SMPS)
- ◆ Uninterruptible power supply (UPS)
- ◆ LED lighting power



ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SFS3001T	SOP8-8L	SFS3001T	Pb Free	Reel

ABSOLUTE MAXIMUM RATINGS ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	V
Drain Current	$T_C = 25^{\circ}\text{C}$	I_D	10	A
	$T_C = 100^{\circ}\text{C}$		6	
Drain Current Pulsed(Note 1)		I_{DM}	40	A
Power Dissipation($T_C=25^{\circ}\text{C}$)		P_D	2.5	W
Single Pulsed Avalanche Energy (Note 2)		E_{AS}	56.25	mJ
Operation Junction Temperature Range		T_J	$-55\sim+150$	$^{\circ}\text{C}$
Storage Temperature Range		T_{stg}	$-55\sim+150$	$^{\circ}\text{C}$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		TL	300	$^{\circ}\text{C}$

THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	50	$^{\circ}\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	86	$^{\circ}\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain -Source Breakdown Voltage	$B_{V_{DS}}$	$V_{GS}=0V \ I_D=250\mu\text{A}$	30	--	--	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=30V \ V_{GS}=0V$	--	--	1	A
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=20V \ V_{DS}=0V$	--	--	100	nA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=-20V \ V_{DS}=0V$	--	--	-100	
On Characteristics						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS} \ I_D=250\mu\text{A}$	1.0	1.6	2.0	V
Static Drain- Source On State Resistance	$R_{DS(on)}$	$V_{GS}=10V \ I_D=10A$	--	9.0	12.5	m Ω
		$V_{GS}=4.5V \ I_D=5.0A$	--	14	18	
Dynamic Characteristics						
Gate Resistance	R_g	$V_{GS}=0V \ f=1.0\text{MHZ}$	--	2.8	--	Ω
Input Capacitance	C_{iss}	$V_{DS}=15V$ $V_{GS}=0V$ $f=1.0\text{MHZ}$	--	1250	--	pF
Output Capacitance	C_{oss}		--	297	--	
Reverse Transfer Capacitance	C_{rss}		--	178	--	
Switching Characteristics						
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=25V \ V_{GS}=10V$ $R_G=6\Omega \ I_D=1A$ (Note 3.4)	--	30.5	--	ns
Turn-on Rise Time	t_r		--	20.6	--	
Turn-off Delay Time	$t_{d(off)}$		--	101.7	--	
Turn-off Fall Time	t_f		--	79.6	--	

Total Gate Charge	Q_g	$V_{DS}=15V$ $I_D=10A$ $V_{GS}=5V$ (Note 3.4)	--	13.5	--	nc
Gate-Source Charge	Q_{gs}		--	5.8	--	
Gate-Drain Charge	Q_{gd}		--	3.6	--	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_S	Integral Reverse P-N Junction Diode in the MOSFET	--	--	10	A
Pulsed Source Current	I_{SM}		--	--	40	
Diode Forward Voltage	V_{SD}	$I_S=12A$ $V_{GS}=0V$	--	--	1.4	V

- 1.Pulse width limited by maximum junction temperature
- 2.L=0.5mH, $V_{DD}=15V$, $V_G=10V$, $R_G=25\Omega$, starting $T_J=25^\circ C$
- 3.Pulse Test: Pulse width $\leq 300\mu s$, Duty cycle $\leq 2\%$
- 4.Essentially independent of operating temperature

Typical Electrical and Thermal Characteristics (Curves)

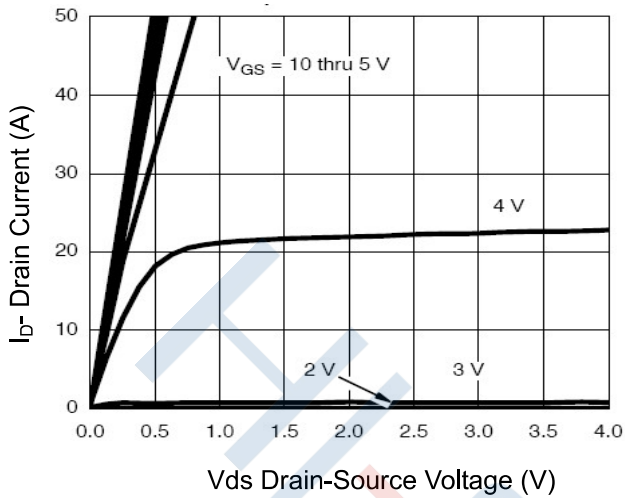


Figure 1 Output Characteristics

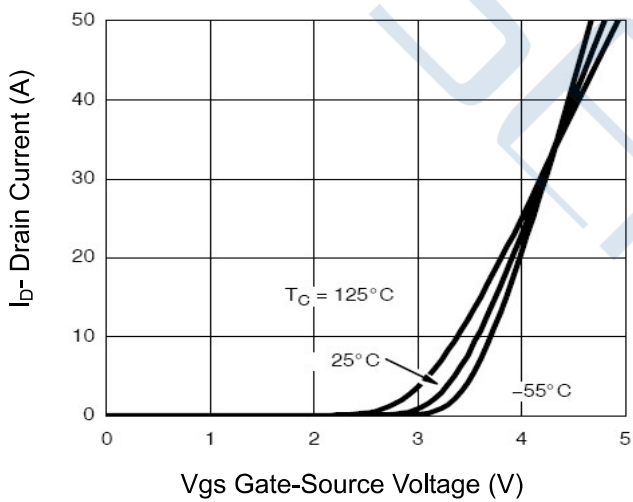


Figure 2 Transfer Characteristics

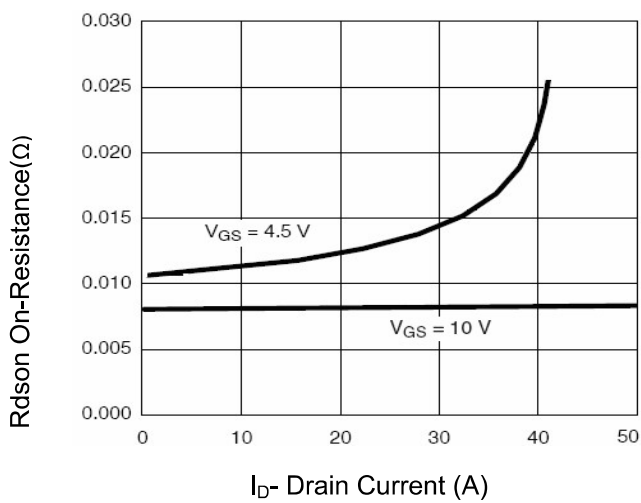


Figure 3 Rdson- Drain Current

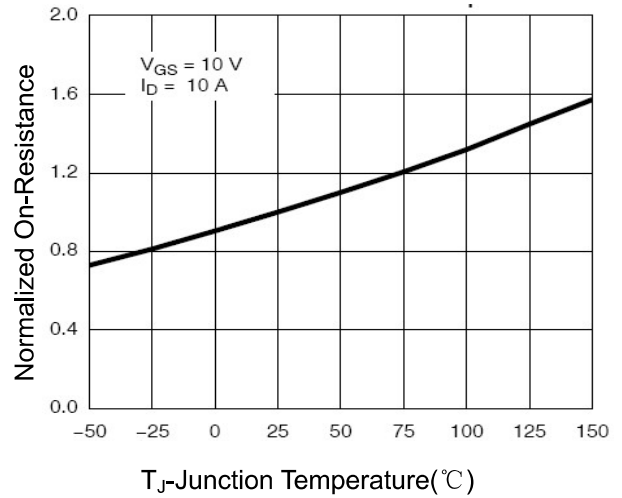


Figure 4 Rdson-Junction Temperature

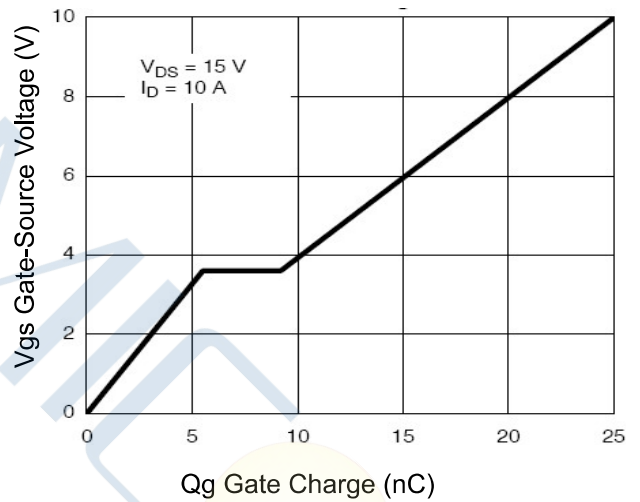


Figure 5 Gate Charge

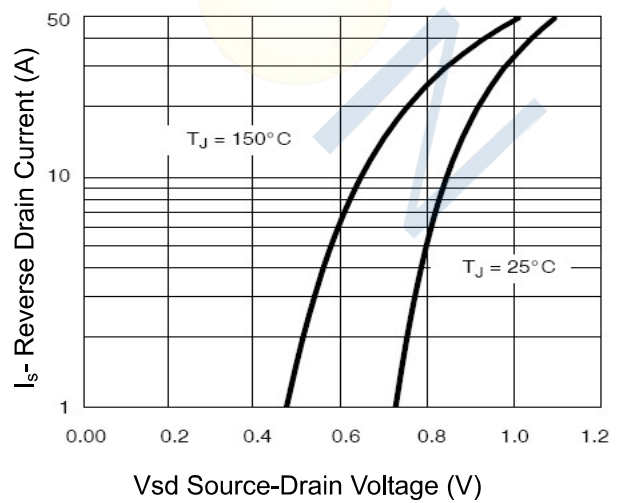


Figure 6 Source- Drain Diode Forward

Typical Performance Characteristics

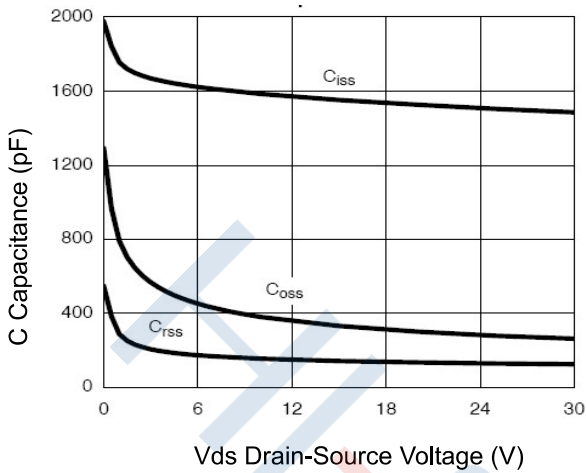


Figure 7 Capacitance vs Vds

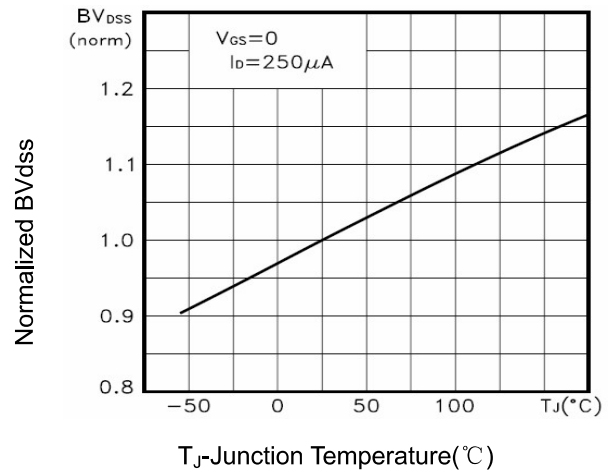


Figure 9 BV_{DSS} vs Junction Temperature

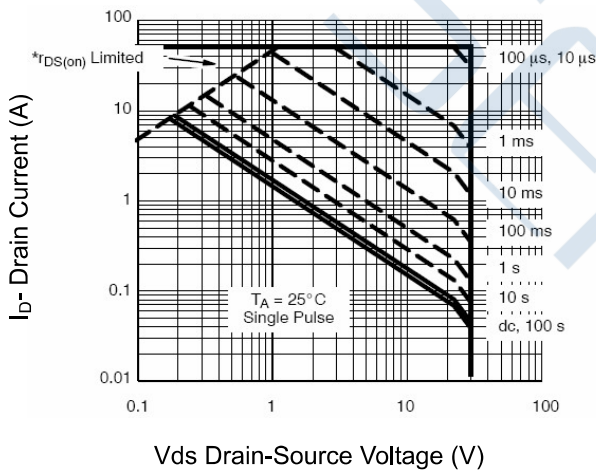


Figure 8 Safe Operation Area

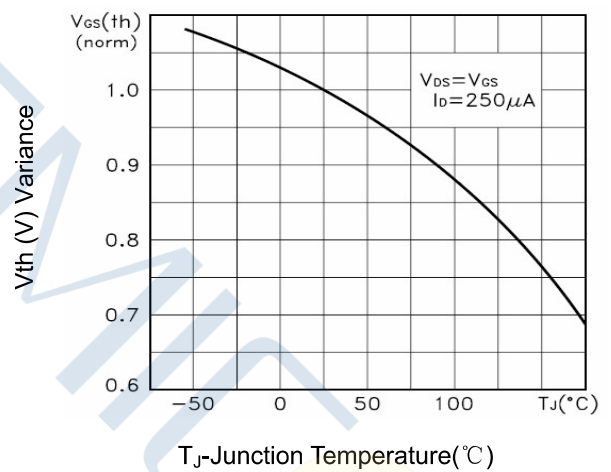
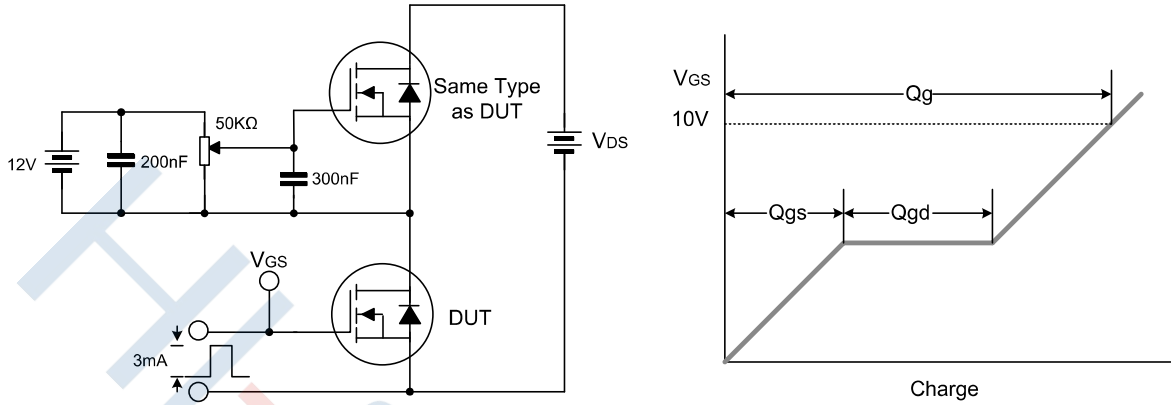


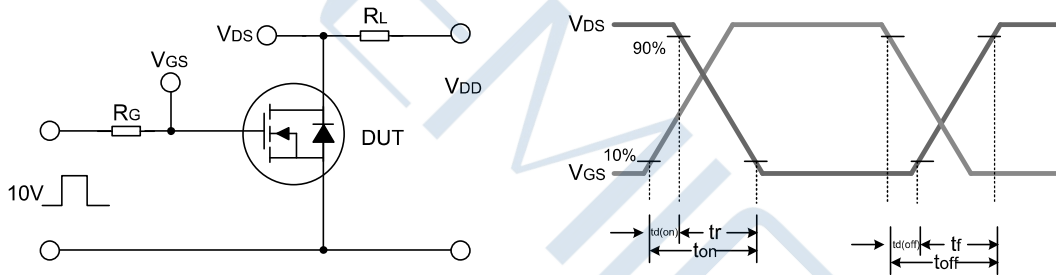
Figure 10 V_{GS(th)} vs Junction Temperature

Test Circuit

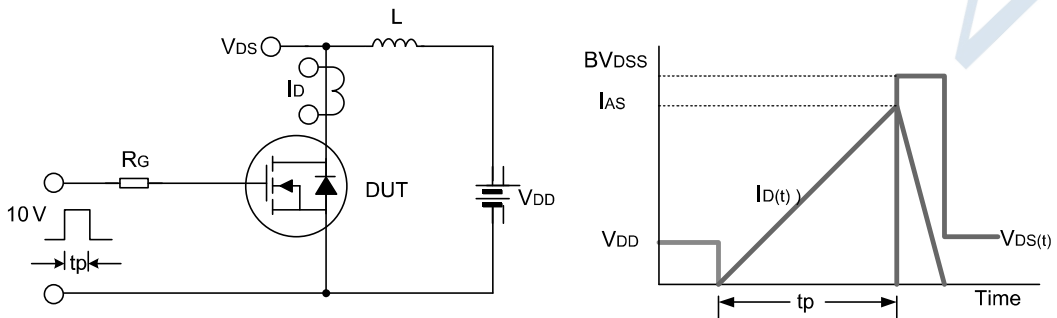
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform

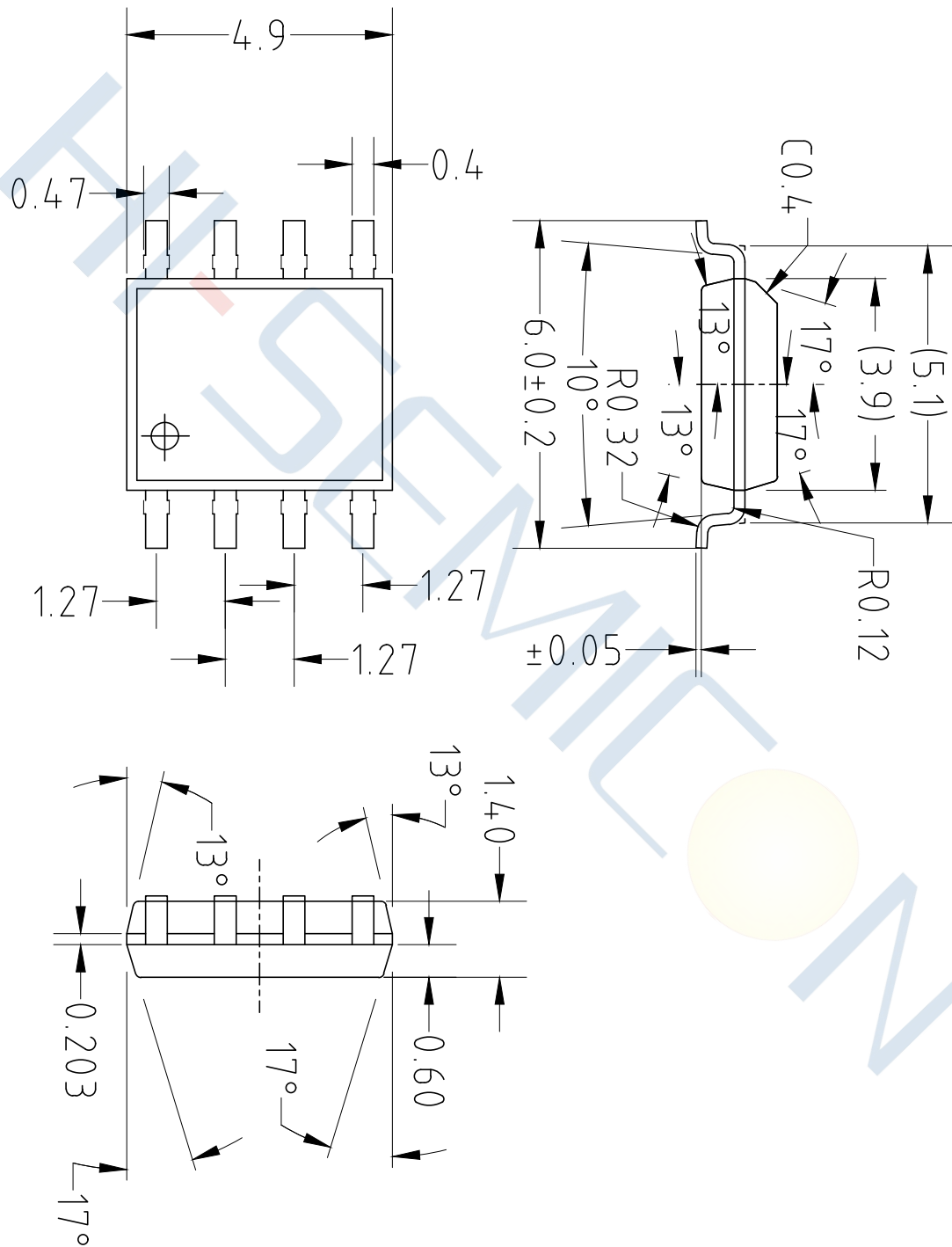


Unclamped Inductive Switching Test Circuit & Waveform



Package Dimensions of SOP8-8L

Unit:mm



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